Product data sheet

1. General description

An AC Thyristor power switch with very high noise immunity and over-voltage protection configured for negative gate triggering in a SOT96-1 (SO8) small surface-mountable plastic package

2. Features and benefits

- Exclusive negative gate triggering
- · Full cycle AC conduction
- High noise immunity
- Remote gate separates the gate driver from the effects of the load current
- Surface-mountable package
- · Very sensitive gate for lowest gate trigger current
- Safe clamping of low energy over-voltage transients
- Self-protective turn-on during high energy voltage transients

3. Applications

- · Fan motor circuits
- · Pump motor circuits
- · Lower-power highly inductive, resistive and safety loads

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DRM}	repetitive peak off- state voltage			-	-	600	V
I _{T(RMS)}	RMS on-state current	full sine wave; $T_{amb} \le 100 \text{ °C}$; $\overline{Fig. 1}$; $\overline{Fig. 2}$		-	-	0.2	Α
I _{TSM}	non-repetitive peak on- state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 16.7 \text{ ms}$		-	-	8.8	Α
		full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig. 3; Fig. 4		-	-	8	Α
Tj	junction temperature			-	-	125	°C
V _{PP}	peak pulse voltage	T _j = 25 °C; non-repetitive, off-state; Fig. 5		-	-	2	kV
Static characteristics							
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 100 \text{ mA}; LD+ G-;$ $T_j = 25 \text{ °C}; Fig. 7$		0.5	-	5	mA

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		$V_D = 12 \text{ V}; I_T = 100 \text{ mA}; LD- G-;$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$	0.5	-	5	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	_	-	20	mA
V _T	on-state voltage	I _T = 0.3 A; T _j = 25 °C; <u>Fig. 10</u>	-	-	1.2	V
V_{CL}	clamping voltage	I_{CL} = 0.1 mA; t_p = 1 ms; T_j = 125 °C	650	-	-	V
Dynamic char	ateristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 402 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 11	300	-	-	V/µs
dl _{com} /dt	rate of change of commutating current	V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 1 A; dV_{com}/dt = 15 V/ μ s; gate open circuit; Fig. 12; Fig. 13	0.15	-	-	A/ms

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	n.c.	not connected	8 <u> </u>	LD -
2	LD	Load		
3	n.c.	not connected		G -• [
4	n.c.	not connected		CM 001aaj924
5	G	Gate	SO8 (SOT96-1)	
6	CM	Common		
7	СМ	Common		
8	n.c.	not connected		

6. Ordering information

Table 3. Ordering information

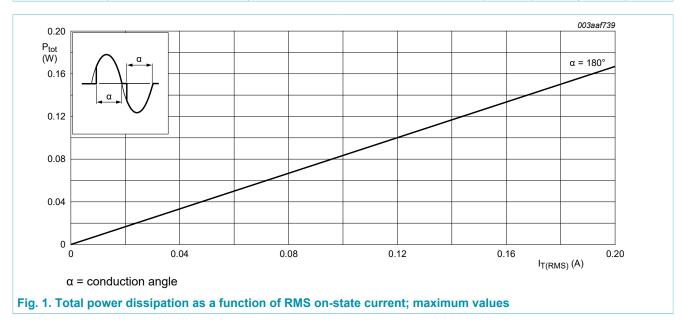
Type number	Package		
	Name	Description	Version
ACT102H-600D	SO8	plastic small outline package; 8 leads; body width 3.9 mm	SOT96-1

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	600	V
I _{T(RMS)}	RMS on-state current	full sine wave; T _{amb} ≤ 100 °C; <u>Fig. 1;</u> <u>Fig. 2</u>	-	0.2	А
I _{TSM}	non-repetitive peak on-	full sine wave; $T_{j(init)} = 25 ^{\circ}C$; $t_p = 16.7 \text{ms}$	-	8.8	Α
	state current	full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 3; Fig. 4	-	8	А
l ² t	I ² t for fusing	t _p = 10 ms; SIN	-	0.31	A²s
dl _T /dt	rate of rise of on-state current	I _G = 10 mA	-	50	A/µs
I _{GM}	peak gate current	t = 20 μs	-	1	Α
P_{GM}	peak gate power		-	2	W
$P_{G(AV)}$	average gate power	over any 20 ms period	-	0.1	W
T _{stg}	storage temperature		-40	150	°C
Tj	junction temperature		-	125	°C
V_{PP}	peak pulse voltage	T _j = 25 °C; non-repetitive, off-state; Fig. 5	-	2	kV



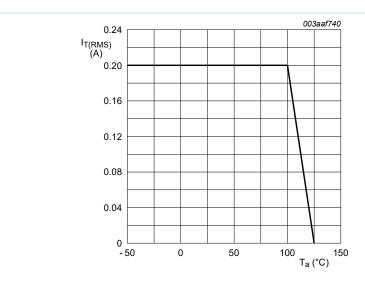


Fig. 2. RMS on-state current as a function of solder point temperature; maximum values

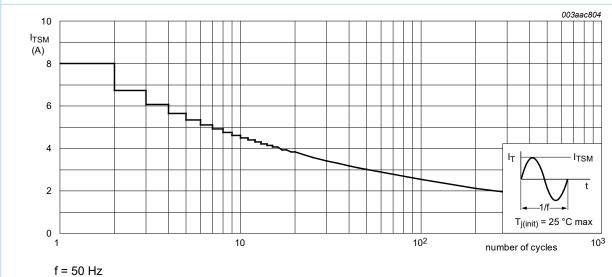
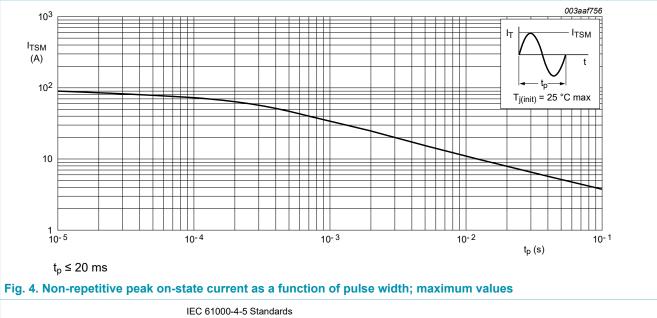


Fig. 3. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



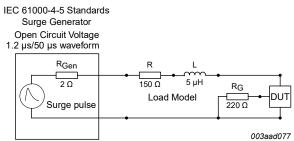
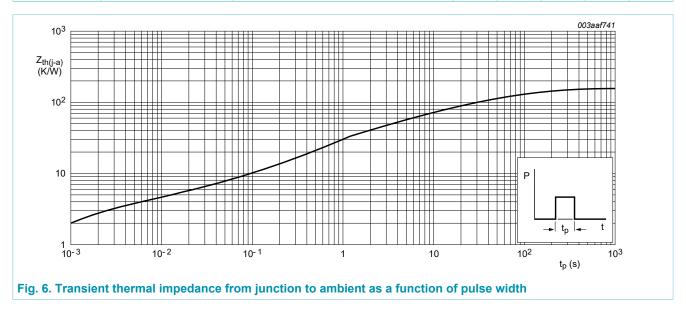


Fig. 5. Test circuit for inductive and resistive loads with conditions equivalent to IEC 61000-4-5

8. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
R _{th(j-a)}	thermal resistance from junction to ambient free air	full cycle; Fig. 6	-	150	-	K/W	



9. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static char	acteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G-;}$ $T_j = 25 \text{ °C; } \frac{\text{Fig. 7}}{}$	0.5	-	5	mA
		$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD- G-;}$ $T_j = 25 \text{ °C; } \frac{\text{Fig. 7}}{}$	0.5	-	5	mA
lL	latching current	$V_D = 12 \text{ V; } I_G = 100 \text{ mA; LD+ G-;}$ $T_j = 25 \text{ °C; } \frac{\text{Fig. 8}}{\text{C}}$	-	-	25	mA
		$V_D = 12 \text{ V; } I_G = 100 \text{ mA; LD- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	25	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	-	20	mA
V _T	on-state voltage	I _T = 0.3 A; T _j = 25 °C; <u>Fig. 10</u>	-	-	1.2	V
V _{GT}	gate trigger voltage	V _D = 400 V; I _T = 100 mA; T _j = 125 °C	0.15	-	-	V
		V _D = 12 V; I _T = 100 mA; T _j = 25 °C	-	-	0.9	V
I _D	off-state current	V _D = 600 V; T _j = 25 °C	-	-	2	μΑ
		V _D = 600 V; T _j = 125 °C	-	-	0.2	mA
V _{CL}	clamping voltage	I_{CL} = 0.1 mA; t_p = 1 ms; T_j = 125 °C	650	-	-	V
Dynamic cl	harateristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 402 V; T_j = 125 °C; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 11	300	-	-	V/µs
dl _{com} /dt	rate of change of commutating current	V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 1 A; dV_{com}/dt = 15 V/ μ s; gate open circuit; Fig. 12; Fig. 13	0.15	-	-	A/ms

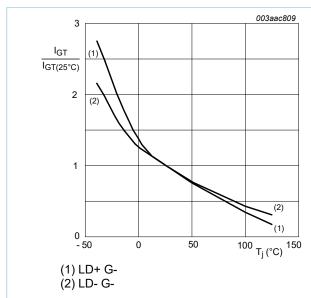


Fig. 7. Normalized gate trigger current as a function of junction temperature

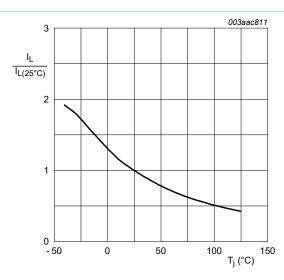


Fig. 8. Normalized latching current as a function of junction temperature

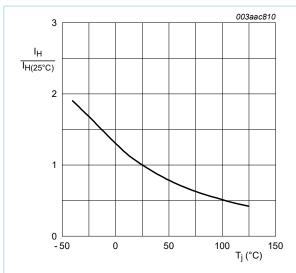
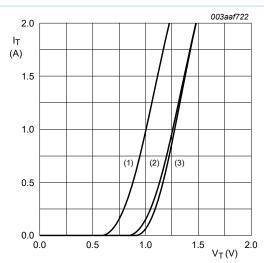


Fig. 9. Normalized holding current as a function of junction temperature



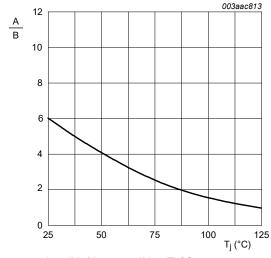
 $V_o = 0.758 \text{ V}; R_s = 0.263 \Omega$

(1) T_j = 125 °C; typical values

(2) T_i = 125 °C; maximum values

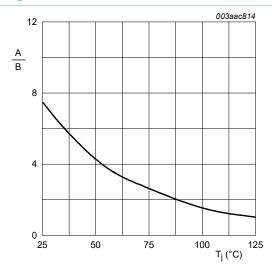
(3) T_i = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage



A = dV_D/dt at condition T_j °C B = dV_D/dt at condition T_i [125] °C

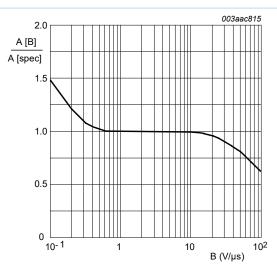
Fig. 11. Normalized rate of rise of off-state voltage as a function of junction temperature



A = dI_{com}/dt at condition T_j °C B = dI_{com}/dt at condition T_j [125] °C

 $V_D = 400 \text{ V}$

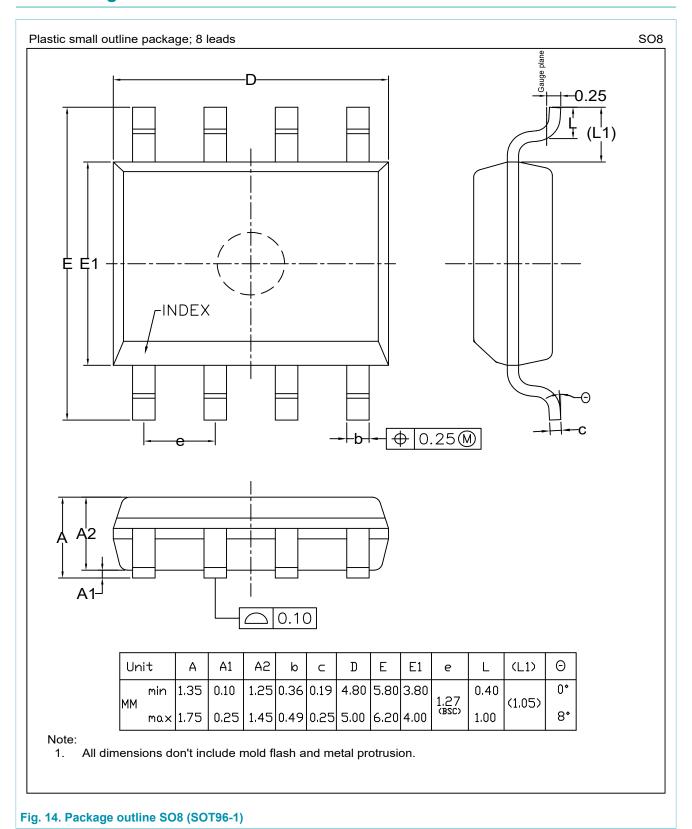
Fig. 12. Normalized critical rate of rise of commutating current as a function of junction temperature



A [B] = dI_{com}/dt at condition B, dV_{com}/dt A [spec] is the data sheet value for dI_{com}/dt turn-off time is less than 20 ms

Fig. 13. Normalized critical rate of change of commutating current as a function of critical rate of change of commutating voltage; minimum values

10. Package outline



ACT102H-600D

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Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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